

Application/Control No.	Applicant(s)/Patent under Reexamination
10/608,771	EIDEN, NIKO
Examiner	Art Unit
Duc M. Nguyen	2685

SEARCHED				
Class	Subclass	Date	Examiner	
455	567			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	10/22/2005	DN		
EAST	10/27/2005	DN		
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